Additional Function Kit for the EDX-LE

Add general analysis functions to the EDX-LE RoHS/ELV screening model.

Features available after installing the kit:

1. Elements not subject to RoHS/ELV regulations can be identified and quantitated.
2. Detailed measurement and analysis conditions can be created according to the application.
3. Film FP method allows analysis of multilayer film thickness, composition, and deposit volume.

Note: There are some precautions regarding analysis performed after installing the kit. Please refer to the specifications, supplied separately, and check applicability.
Example of Measurements Using the Additional Function Kit

### Qualitative/Quantitative Analysis

**Qualitative profile of stainless steel**

**Quantitative analysis results (FP method) for stainless steel**

Measurement results for Au/Ni/Fe-based plating thickness

### Thin Film Analysis

**Measurement spectra of Au/Ni/Fe-based plating**

### Matching (steel type identification, product identification)

Matching results

Note: This kit may not be applicable to some sample/film materials or film thicknesses.

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